Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/772,435	SHIRAISHI ET AL.	
Examiner	Art Unit	
John J. Goodrow	1756	

	SEARCHED			
Class	Subclass	Date	Examiner	
430	109.4	4/17/2006	JG	
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INT	NTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

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